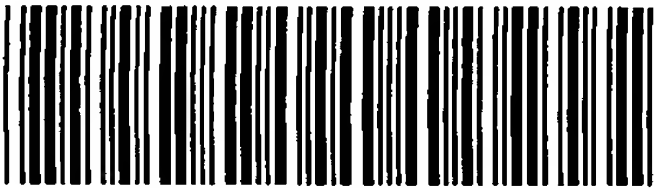


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/026,618	LEE ET AL.	
	Examiner	Art Unit	
	Emmanuel Bayard	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	316	5/16/2007	EB
375	326	5/16/2007	EB
375	327	5/16/2007	EB
375	340	5/16/2007	EB
375	324	5/16/2007	EB
375	344	5/16/2007	EB
375	345	5/16/2007	EB
375	354	5/16/2007	EB

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	354	5/16/2007	EB
375	316	5/16/2007	EB

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East	5/16/2007	EB